

SC12598TK

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

Page 1 of 1

PATENT NO.: 6937047 B2
APPLICATION NO: 10/634484
DATE: 08-05-2003
FIRST NAMED INVENTOR: TRAN, TU-ANH

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

No In ~~Column 6, Line 21, Claim No. 7:~~

Change ~~"(BIST) circuitry" to (BIST) circuitry~~

In Column 6, Line 28, Claim No. 9:

Change "100 μ m x 200" to ~~—100 μ m x 200—~~

In Column 6, Line 37, Claim No. 12:

Change "one lest pad" to ~~—one test pad—~~

No In ~~Column 7, Line 25, Claim No. 28:~~

Change ~~"plurality bond pads" to — plurality of bond pads—~~

MAILING ADDRESS OF SENDER (Please do not use customer number below)

Freescale Semiconductor, Inc.
Law Department
7700 West Parmer Lane PL02
Austin, TX 78729

Copy VT